

Source	Size
<i>Flavor-symmetric backgrounds</i>	
$r_{\mu/e}$ residual dependencies	5% flat
	5% p_T -dependent
	5% η -dependent
R_T uncertainty	4–5%
Statistical uncertainty in DF sideband	✓
κ uncertainty (on-Z SRs only)	20%
p_T^{miss} templates	
Closure in simulations	20–100%
Statistical uncertainty in γ +jets sample	✓
Statistical uncertainty in normalization bin	✓
EW subtraction	30% of EW yield in γ +jets sample
$r_{in/out}$ (edge SRs only)	50–100%
<i>DY+jets in slepton SRs</i>	
$r_{in/out}$ (slepton SRs only)	50%